

UTC UNISONIC TECHNOLOGIES CO., LTD

1N70K-TA **Preliminary Power MOSFET**

1.2A, 700V N-CHANNEL **POWER MOSFET**

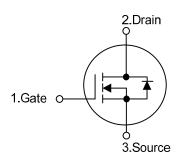
DESCRIPTION

The UTC 1N70K-TA is a high voltage MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

FEATURES

- * $R_{DS(ON)}$ < 13.5 Ω @ V_{GS} = 10V, I_{D} = 0.5A
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

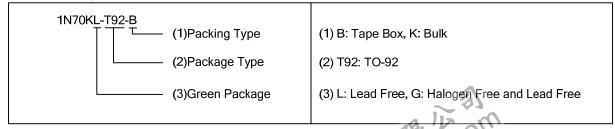
SYMBOL



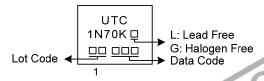
ORDERING INFORMATION

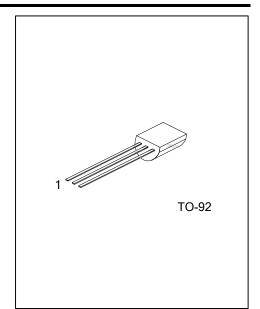
Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
1N70KL-x-T92-B	1N70KG-x-T92-B	TO-92	G	D	S	Tape Box	
1N70KL-x-T92-K	1N70KG-x-T92-K	TO-92	G	D	S	Bulk	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING





www.unisonic.com.tw 1 of 5

■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

PARAMETE	SYMBOL	RATINGS	UNIT	
Drain-Source Voltage	V_{DSS}	700	V	
Gate-Source Voltage	V_{GSS}	±30	V	
Continuous Drain Current	Continuous	I_{D}	1.0	Α
Pulsed Drain Current	Pulsed (Note 2)	I_{DM}	4.0	Α
Avalanche Current (Note 2)	I_{AR}	1.0	Α	
Single Pulsed Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	5	mJ
Peak Diode Recovery dv/dt (Note 4	dv/dt	4.5	V/ns	
Power Dissipation	P_{D}	1.6	W	
Junction Temperature	TJ	+150	°C	
Storage Temperature	T_{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 10mH, I_{AS} = 1.0A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 4. $I_{SD} \le 1.0A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ °C.

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	140	°C/W	
Junction to Case	θ_{JC}	80	°C/W	

■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

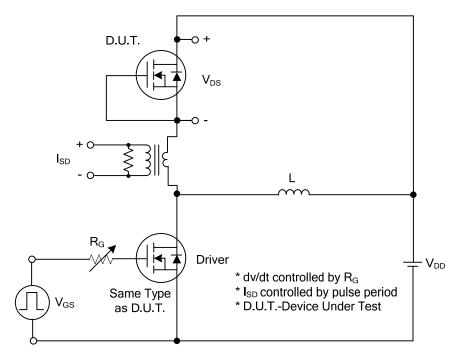
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	700			V	
Drain-Source Leakage Current		I_{DSS}	$V_{DS} = 700V, V_{GS} = 0V$			1	μΑ	
Gate-Source Leakage Current	Forward	I _{GSS}	$V_{GS} = 30V, V_{DS} = 0V$			100	nA	
	Reverse		$V_{GS} = -30V, V_{DS} = 0V$			-100	nA	
ON CHARACTERISTICS								
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V	
Static Drain-Source On-State Resistance		R _{DS(ON)}	$V_{GS} = 10V, I_D = 0.5A$			13.5	Ω	
DYNAMIC CHARACTERISTICS								
Input Capacitance		C _{ISS}			190		pF	
Output Capacitance		Coss	V _{DS} =25V, V _{GS} =0V, f=1MHz		25		pF	
Reverse Transfer Capacitance		C_{RSS}			10		pF	
SWITCHING CHARACTERISTIC	S							
Rise Time (Note 1)		Q_G	\/ -E0\/ \/ -10\/ -1.2A		14		nC	
Turn-OFF Delay Time		Q_GS	V _{DS} =50V, V _{GS} =10V, I _D =1.3A, I _G =100μA (Note 1, 2)		2.8		nC	
Fall-Time		Q_GD	IG-100μΑ (Note 1, 2)		1		nC	
Total Gate Charge (Note 1)		$t_{D(ON)}$			35		ns	
Gate to Source Charge		t _R	V_{DD} =30V, V_{GS} =10V,		20		ns	
Gate to Drain Charge		t _{D(OFF)}	I _D =0.5A, R _G =25Ω (Note 1, 2)		45		ns	
Turn-ON Delay Time		t_{F}			8		ns	
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current		Is	SP-CO	, ,		1.0	Α	
Maximum Body-Diode Pulsed Current		I _{SM}	4 18 (30.			4.0	Α	
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I _S =1.0A, V _{GS} =0V			1.4	V	
Body Diode Reverse Recovery Time (Note 1)		t _{rr}	I _S =1.0A, V _{GS} =0V,		310		nS	
Body Diode Reverse Recovery Charge		Q_{rr}	dl _F /dt=100A/µs		0.65		μC	

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%.

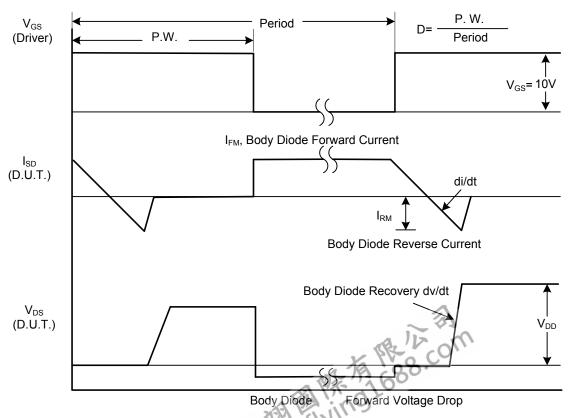
2. Essentially independent of operating temperature.



■ TEST CIRCUITS AND WAVEFORMS

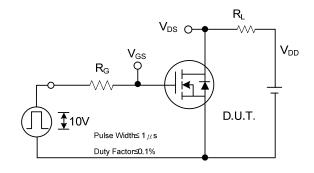


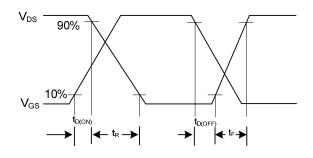
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

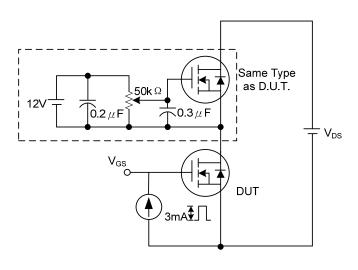
TEST CIRCUITS AND WAVEFORMS (Cont.)

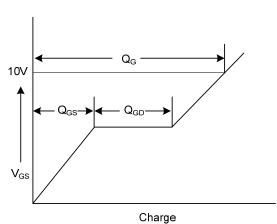




Switching Test Circuit

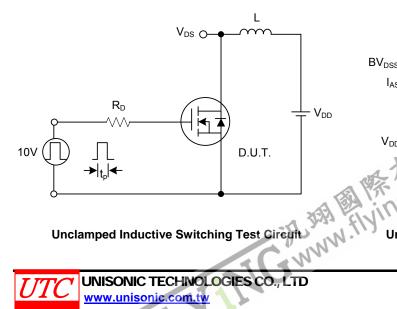
Switching Waveforms

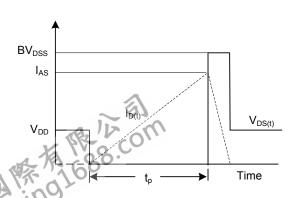




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Waveforms

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